

SCIENTIFIC REPORTS

OPEN

Publisher Correction: Large anisotropy of ferroelectric and pyroelectric properties in heteroepitaxial oxide layers

R. Moalla¹, S. Cueff¹, J. Penuelas¹, B. Vilquin¹, G. Saint-Girons¹, N. Baboux² & R. Bachelet¹

Correction to: *Scientific Reports* <https://doi.org/10.1038/s41598-018-22349-y>, published online 12 March 2018

In the original version of the Article, the following text was duplicated in the ‘Results and Discussion’ section:

“(For the out-of-plane (OOP) measurement in a metal-ferroelectric-metal (MFM) structure, the electric field lines pass across the PZT layer vertically toward the bottom electrode, the properties thus obtained, such as P_r , E_c , p etc, are those of the layer in the direction perpendicular to the surface. For in-plane (IP) measurement, two successive fingers belong to two different combs inversely polarized. Due to the absence of the lower conductive layer, the field lines pass through the PZT layer horizontally from one finger to the next. Properties thus extracted are those of the layer in the direction parallel to the surface. We consider that one of the two combs is the equivalent of the upper electrode of a plate capacitor and the second is the equivalent of the lower electrode, so the distance between two successive fingers is equivalent to the thickness of the layer between the electrodes. The total area of the capacitor is considered as the number of fingers in a comb multiplied by the surface of a finger)”

This has now been corrected in the HTML and PDF versions of the Article.



Open Access This article is licensed under a Creative Commons Attribution 4.0 International License, which permits use, sharing, adaptation, distribution and reproduction in any medium or format, as long as you give appropriate credit to the original author(s) and the source, provide a link to the Creative Commons license, and indicate if changes were made. The images or other third party material in this article are included in the article’s Creative Commons license, unless indicated otherwise in a credit line to the material. If material is not included in the article’s Creative Commons license and your intended use is not permitted by statutory regulation or exceeds the permitted use, you will need to obtain permission directly from the copyright holder. To view a copy of this license, visit <http://creativecommons.org/licenses/by/4.0/>.

© The Author(s) 2018

¹Institut des Nanotechnologies de Lyon (INL) - CNRS UMR 5270, Univ. Lyon, Ecole Centrale de Lyon, Bâtiment F7, 36 av. Guy de Collongue, 69134, Ecully Cedex, France. ²Institut des Nanotechnologies de Lyon (INL) - CNRS UMR 5270, Univ. Lyon, INSA de Lyon, Bâtiment Blaise Pascal, 7 avenue Jean Capelle, 69621, Villeurbanne Cedex, France. Correspondence and requests for materials should be addressed to R.B. (email: romain.bachelet@ec-lyon.fr)